

<b>Notic of References Cited</b>	Application/Control No. 10/006,757	Applicant(s)/Patent Under Reexamination MILLER ET AL.	
	Examiner Tan Ho	Art Unit 2821	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,570,545 B1	05-2003	Snow et al.	343/915
	B	US-6,545,606 B2	04-2003	Piri et al.	340/573.1
	C	US-6,512,496 B2	01-2003	Alexeff et al.	343/915
	D	US-6,225,940 B1	05-2001	Ohlsen, Kenneth A.	342/5
	E	US-5,969,660 A	10-1999	Veazey, Sidney E.	342/8
	F	US-5,457,472 A	10-1995	Bjordal et al.	343/912
	G	US-3,671,965	06-1972	David W. Rabenhorst; et. al.	342/8
	H	US-3,618,150	11-1971		441/16
	I	US-2,888,675	05-1959	AMASA PRATT; et. al.	342/8
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	V	
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	X	

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